

MOS FIELD EFFECT TRANSISTOR 2SJ492

SWITCHING P-CHANNEL POWER MOS FET INDUSTRIAL USE

DESCRIPTION

This product is P-Channel MOS Field Effect Transistor designed for DC/DC converters and motor/lamp driver circuits.

ORDERING INFORMATION

PART NUMBER	PACKAGE
2SJ492	TO-220AB
2SJ492-S	TO-262
2SJ492-ZJ	TO-263

FEATURES

- Low on-state resistance $R_{DS(on)1} = 100 \text{ m}\Omega \text{ (MAX.)} (V_{GS} = -10 \text{ V}, I_D = -10 \text{ A})$ $R_{DS(on)2} = 185 \text{ m}\Omega \text{ (MAX.)} (V_{GS} = -4 \text{ V}, I_D = -10 \text{ A})$
- Low Ciss: Ciss = 1210 pF (TYP.)
- Built-in gate protection diode

ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

VDSS	-60	V
VGSS(AC)	∓ 20	V
VGSS(DC)	-20, 0	V
D(DC)	∓ 20	А
D(pulse)	∓ 80	А
Р⊤	1.5	W
Рт	70	W
Tch	150	°C
Tstg	–55 to +150	°C
AS	-20	А
Eas	40	mJ
	VGSS(AC) VGSS(DC) ID(DC) ID(pulse) PT PT Tch Tstg IAS	VGSS(AC) ∓ 20 VGSS(DC) −20, 0 ID(DC) ∓ 20 ID(pulse) ∓ 80 PT 1.5 PT 70 Tch 150 Tstg −55 to +150 IAS −20

Notes 1. f = 20 kHz, Duty Cycle $\leq 10\%$ (+Side)

- **2.** PW \leq 10 μ s, Duty Cycle \leq 1 %
- 3. Starting T_{ch} = 25 °C, R_A = 25 Ω , V_{GS} = -20 V \rightarrow 0

THERMAL RESISTANCE

Channel to Case	Rth(ch-C)	1.79	°C/W
Channel to Ambient	Rth(ch-A)	83.3	°C/W

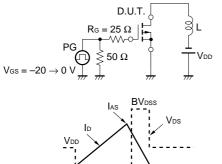
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ELECTRICAL CHARACTERISTICS (T_A = 25 °C)

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CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain to Source On-state Resistance	RDS(on)1	$V_{GS} = -10 V$, $I_D = -10 A$		70	100	mΩ
	RDS(on)2	$V_{GS} = -4 V$, $I_D = -10 A$		120	185	mΩ
Gate to Source Cut-off Voltage	VGS(off)	$V_{DS} = -10 V$, $I_D = -1 mA$	-1.0	-1.5	-2.0	V
Forward Transfer Admittance	y _{fs}	$V_{DS} = -10 \text{ V}, \text{ Id} = -10 \text{ A}$	5.0	12		S
Drain Leakage Current	IDSS	$V_{DS} = -60 V, V_{GS} = 0 V$			-10	μA
Gate to Source Leakage Current	lgss	$V_{GS} = \mp 20 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$			∓ 10	μA
Input Capacitance	Ciss	V _{DS} = -10 V		1210		pF
Output Capacitance	Coss	Vgs = 0 V		520		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		180		pF
Turn-on Delay Time	td(on)	ID = -10 A		16		ns
Rise Time	tr	$V_{GS(on)} = -10 V$		140		ns
Turn-off Delay Time	td(off)	$V_{DD} = -30 V$		90		ns
Fall Time	tr	R _G = 10 Ω		80		ns
Total Gate Charge	QG	ID = -20 A		42		nC
Gate to Source Charge	Q _{GS}	$V_{DD} = -48 V$		8.0		nC
Gate to Drain Charge	Qgd	Vgs = -10 V		10		nC
Body Diode Forward Voltage	VF(S-D)	$I_F = -20 \text{ A}, \text{ V}_{GS} = 0 \text{ V}$		1.0		V
Reverse Recovery Time	trr	IF = -20 A, VGS = 0 V		125		ns
Reverse Recovery Charge	Qrr	di/dt = 50 A/ μ s		280		nC

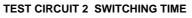
TEST CIRCUIT 1 AVALANCHE CAPABILITY

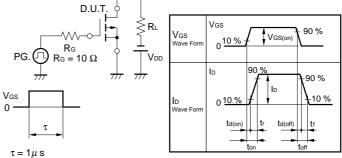


Starting Tch

TEST CIRCUIT 3 GATE CHARGE

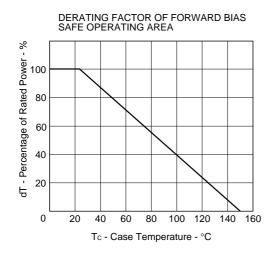
 $PG. \bigoplus_{m} \underbrace{50 \Omega}_{m} \underbrace{50 \Omega}_{m}$



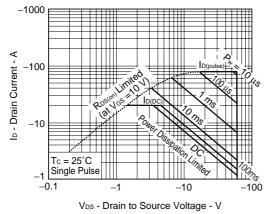


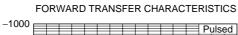
Duty Cycle $\leq 1 \%$

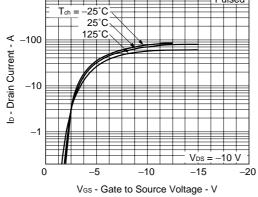
TYPICAL CHARACTERISTICS (TA = 25 °C)

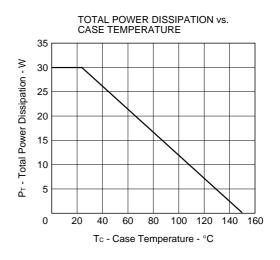


FORWARD BIAS SAFE OPERATING AREA

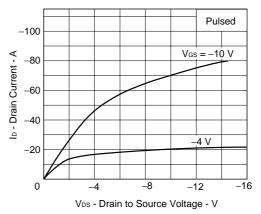


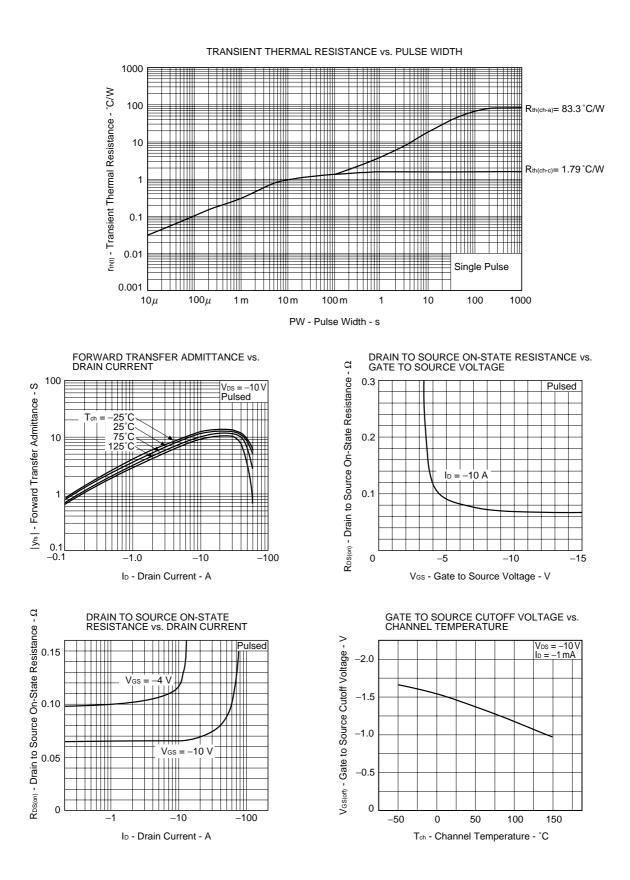


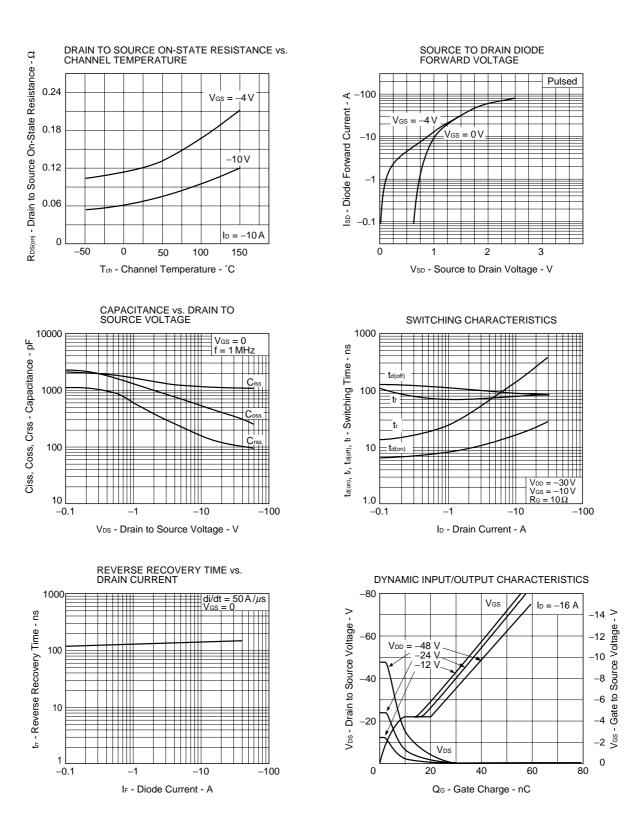




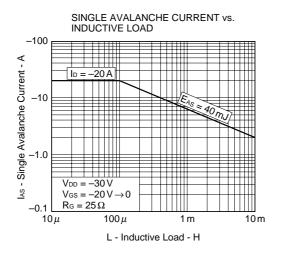




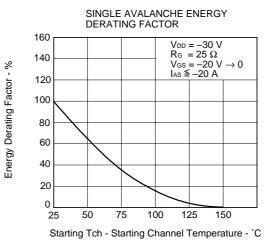




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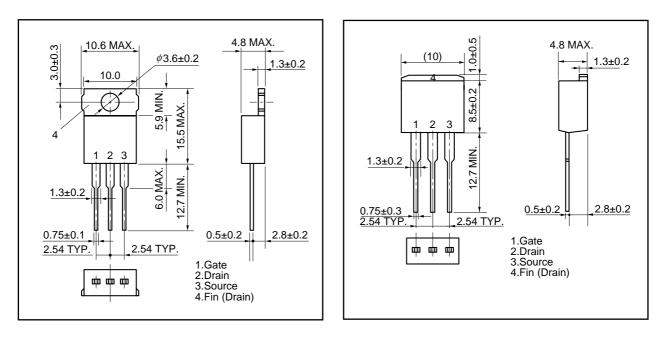
NEC



Data Sheet D11264EJ1V0DS00

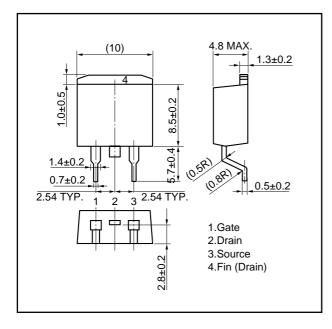
PACKAGE DRAWING (Unit: mm)

1) TO-220AB (MP-25)

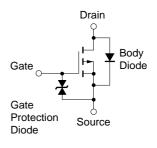


2) TO-262 (MP-25 Fin Cut)

3) TO-263 (JEDEC TYPE: MP-25ZJ)



EQUIVALENT CIRCUIT



Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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Anti-radioactive design is not implemented in this product.